

IRFW830B / IRFI830B

500V N-Channel MOSFET

General Description

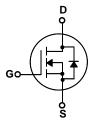
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies, power factor correction and electronic lamp ballasts based on half bridge.

Features

- 4.5A, 500V, $R_{DS(on)}$ = 1.5 Ω @V_{GS} = 10 V Low gate charge (typical 27 nC)
- Low Crss (typical 17 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

Symbol	pol Parameter		IRFW830B / IRFI830B	Units
V_{DSS}	Drain-Source Voltage		500	V
I _D	Drain Current - Continuous (T _C = 25°C	:)	4.5	Α
	- Continuous (T _C = 100°	C)	2.9	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	18	Α
V_{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	270	mJ
I _{AR}	Avalanche Current	(Note 1)	4.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	7.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		3.13	W
	Power Dissipation (T _C = 25°C)		73	W
	- Derate above 25°C	Ī	0.58	W/°C
T _J , T _{stg}	Operating and Storage Temperature Rang	је	-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.71	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		500			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced	to 25°C		0.54		V/°C
I _{DSS}	Zero Coto Vellano Brain Command	V _{DS} = 500 V, V _{GS} = 0 V				10	μΑ
	Zero Gate Voltage Drain Current	V _{DS} = 400 V, T _C = 125°C				100	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
On Cha	racteristics						
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 2.25 A			1.16	1.5	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 2.25 A	(Note 4)		4.2		S
C _{iss}	Output Capacitance Reverse Transfer Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$			76 17	100	pF pF
C _{oss}	Output Capacitance Reverse Transfer Capacitance	f = 1.0 MHz			76 17	100 22	pF pF
Switchi	ing Characteristics						
t _{d(on)}	Turn-On Delay Time	V _{DD} = 250 V, I _D = 4.5 A,			15	40	ns
t _r	Turn-On Rise Time	$V_{DD} = 250 \text{ V, } I_D = 4.5 \text{ A,}$ $R_G = 25 \Omega$			40	90	ns
t _{d(off)}	Turn-Off Delay Time	NG = 20 32			85	180	ns
t _f	Turn-Off Fall Time		(Note 4, 5)		45	100	ns
Qg	Total Gate Charge	V _{DS} = 400 V, I _D = 4.5 A,			27	35	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			4.0		nC
Q _{gd}	Gate-Drain Charge		(Note 4, 5)		12	-	nC
	Source Diode Characteristics a	nd Maximum Ratings	;				
I _S	Maximum Continuous Drain-Source Did	ode Forward Current				4.5	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F					18	Α
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 4.5 \text{ A}$				1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_S = 4.5 \text{ A},$			305		ns
Q _{rr}			(Note 4)				

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. L = 24mH, I_{AS} = 4.5A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
 3. I_{SD} \leq 4.5A, di/dt \leq 300A/µs, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C
 4. Pulse Test : Pulse width \leq 300µs, Duty cycle \leq 2%
 5. Essentially independent of operating temperature

Typical Characteristics

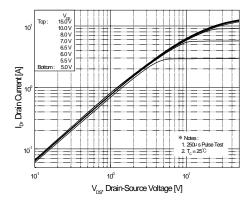


Figure 1. On-Region Characteristics

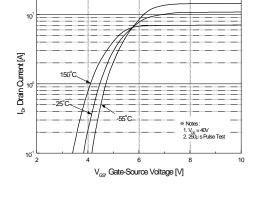


Figure 2. Transfer Characteristics

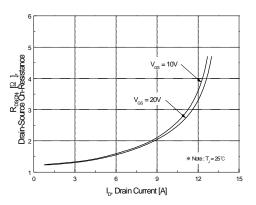


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

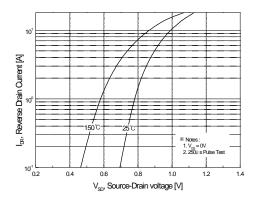


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

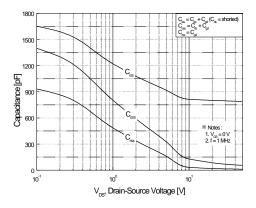


Figure 5. Capacitance Characteristics

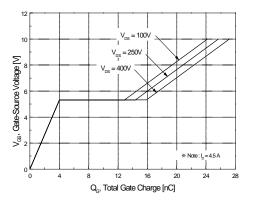


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

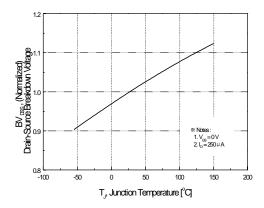


Figure 7. Breakdown Voltage Variation vs Temperature

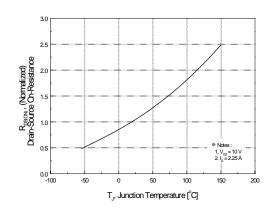


Figure 8. On-Resistance Variation vs Temperature

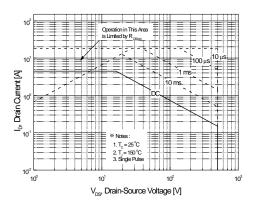


Figure 9. Maximum Safe Operating Area

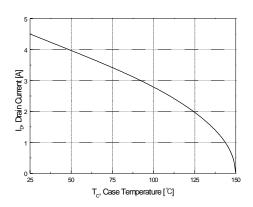


Figure 10. Maximum Drain Current vs Case Temperature

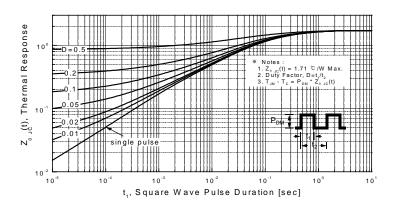
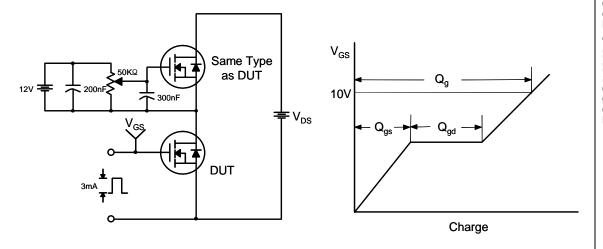


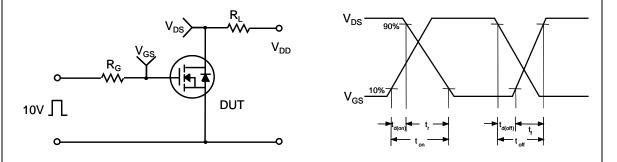
Figure 11. Transient Thermal Response Curve

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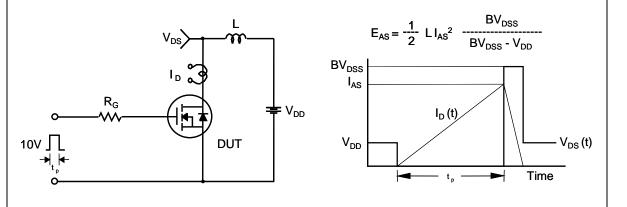
Gate Charge Test Circuit & Waveform



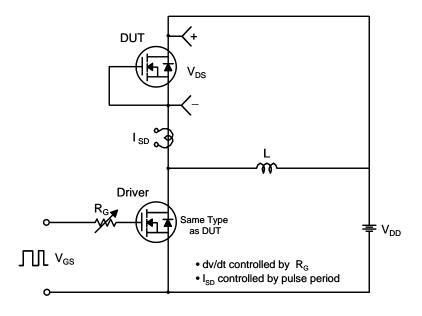
Resistive Switching Test Circuit & Waveforms

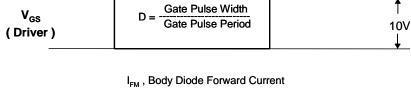


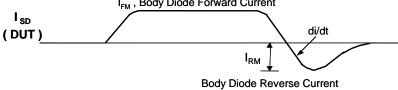
Unclamped Inductive Switching Test Circuit & Waveforms

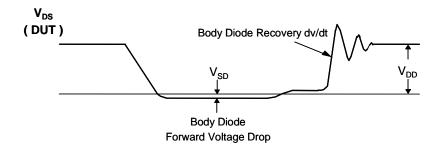


Peak Diode Recovery dv/dt Test Circuit & Waveforms

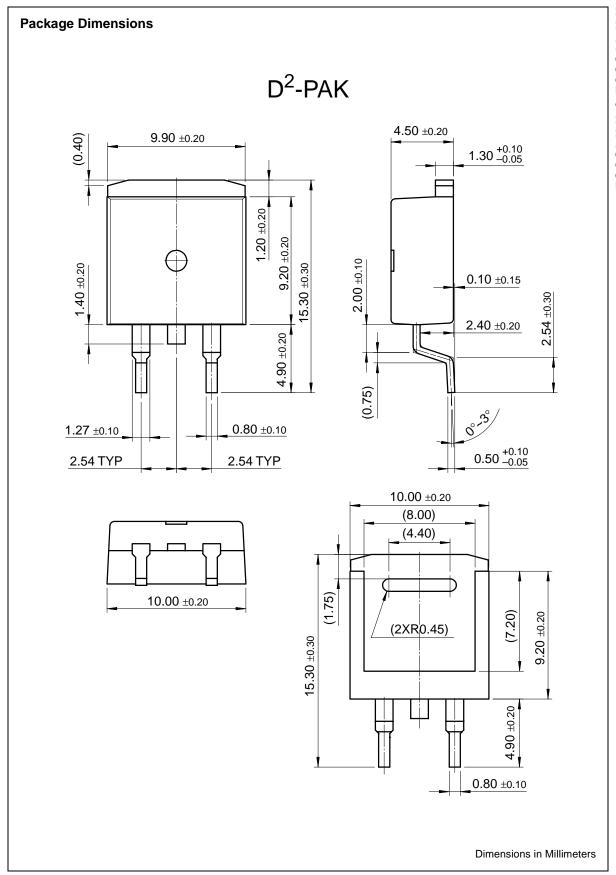


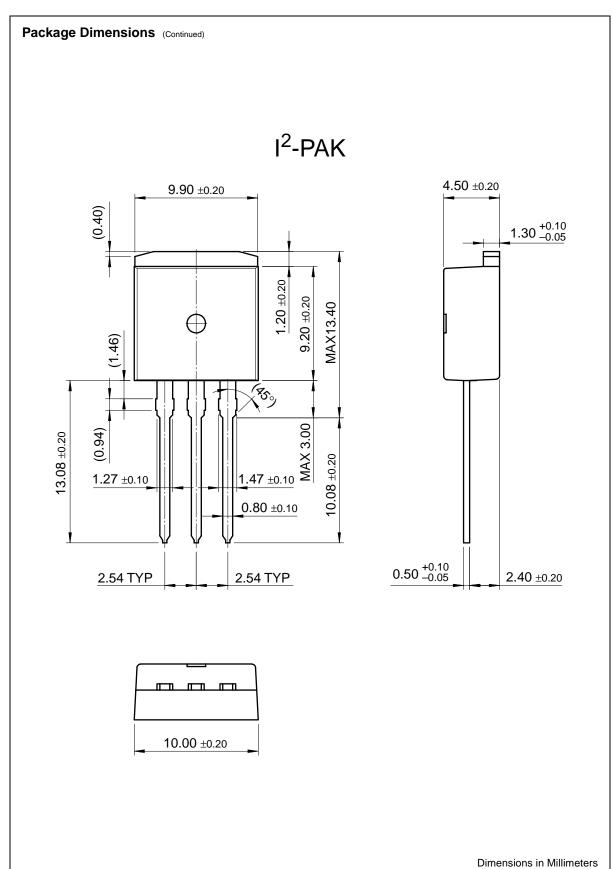






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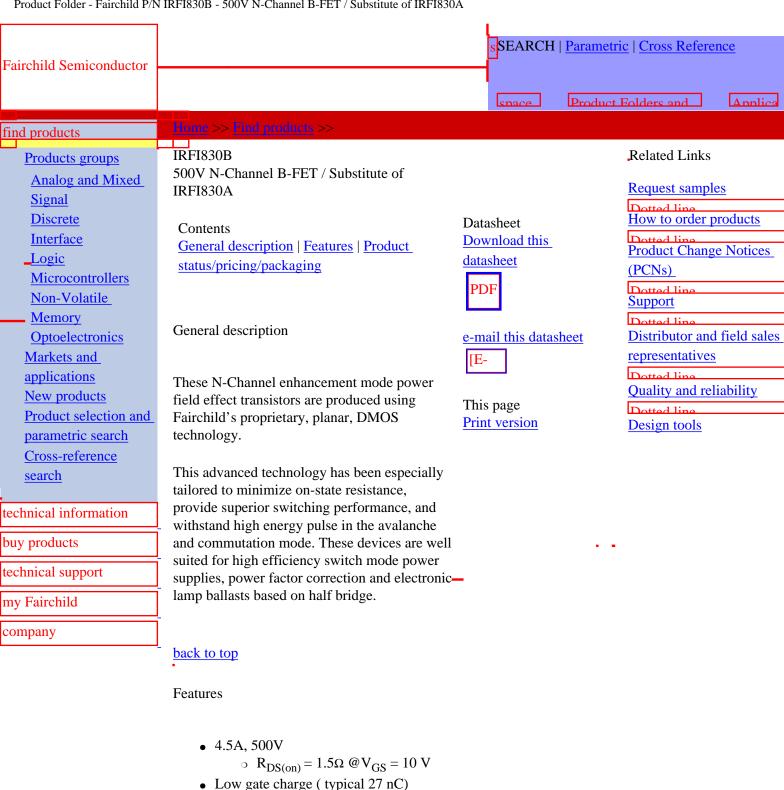
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- Low Crss (typical 17 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

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Product status/pricing/packaging

Product	Product status	Pricing*	Package type	Leads	Packing method	

Product Folder - Fairchild P/N IRFI830B - 500V N-Channel B-FET / Substitute of IRFI830A

IRFI830E	BTU Full Produ	solution \$0.79	TO-262(I2PAK)	3	RAIL

^{* 1,000} piece Budgetary Pricing

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